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PLUS Search Results for S/N 10055088, Searched August 09, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated sear ch

system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that a re

most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

10055088_LIST

5269016	5321354
5940367	5446399
4284522	5600576
5333130	5825191
5533005	4472789
5581713	4795982
5694615	5425035
6373838	5548211
6392401	5673028
6446218	6028441
6453468	6058502
4371832	6087846
5867358	6114181
4324542	3882386
4520348	4039813

10055088 CLS

Most Frequently Occurring Classifications of Patents Returned From A Search of 10055088 on August 09, 2004

Original Classifications 714/732 714/736 3 324/765 2 324/767 2 340/635 2 345/84 2 370/221 2 702/35 2 714/26 714/4 Cross-Reference Classifications 5 714/732 4 714/736 3 324/765 3 324/770 3 340/653 3 714/47 3 714/733 2 307/44 2 307/80 2 324/117R 2 324/537 2 324/543 2 324/73.1 2 340/516 2 345/55 2 359/326 2 361/154 2 370/225 703/2 2 2 713/340 2 714/2 2 714/40 2 714/734 2 714/737

Combined Classifications

9 714/732

714/738

- 8 714/736
- 6 324/765
- 4 714/47

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- 714/733
- 3 324/537
- 3 324/73.1
- 3 324/770
- 3 340/635
- 3 340/653
- 3 370/225
- 3 713/340
- 3 714/4
- 3 714/40
- 3 714/737
- 2 250/221
- 2 307/44
- 2 307/64
- 2 307/80
- 2 324/117R
- 2 324/127
- 2 324/158.1
- 2 324/509
- 2 324/522
- 2 324/543
- 2 324/628
- 2 324/751
- 2 324/767
- 2 340/516
- 2 345/55
- 2 345/84
- 2 359/326
- 2 361/104
- 2 361/154 2 365/201
- 2 370/221
- 2 370/228
- 2
- 702/35
- 2 703/2
- 2 714/11
- 2 714/2
- 2 714/26
- 2 714/724
- 2 714/734
- 714/738

10055088_CLSTITLES
Titles of Most Frequently Occurring Classifications of Patents Returne

From A Search of 10055088 on August 09, 2004

9	714/732 Class 714/699 714/724 714/732	714	: ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY PULSE OR DATA ERROR HANDLING
8		714	OR, 4 XR) : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY PULSE OR DATA ERROR HANDLING .Digital logic testingDevice response compared to expected fault-free response
6		324	: ELECTRICITY: MEASURING AND TESTING FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
4		714	OR, 3 XR) : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING .Reliability and availabilityPerformance monitoring for fault avoidance
4		714	OR, 3 XR) : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY PULSE OR DATA ERROR HANDLING .Digital logic testingBuilt-in testing circuit (BILBO)
3	324/537 Class 324/500	324	OR, 2 XR) : ELECTRICITY: MEASURING AND TESTING FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS .Of individual circuit component or element

10055088 CLSTITLES (1 OR, 2 XR) 3 324/73.1 Class 324: ELECTRICITY: MEASURING AND TESTING PLURAL, AUTOMATICALLY SEQUENTIAL TESTS 324/73.1 (0 OR, 3 XR)324/770 324 : ELECTRICITY: MEASURING AND TESTING Class FAULT DETECTING IN ELECTRIC CIRCUITS AND OF 324/500 ELECTRIC COMPONENTS .Of individual circuit component or element 324/537 ..Liquid crystal device test 324/770 (2 OR, 1 XR) 340/635 340 : COMMUNICATIONS: ELECTRICAL Class CONDITION RESPONSIVE INDICATING SYSTEM 340/500 340/540 .Specific condition .. Condition of electrical apparatus 340/635 (0 OR, 3 XR) 340/653 340 : COMMUNICATIONS: ELECTRICAL CONDITION RESPONSIVE INDICATING SYSTEM 340/500 .Specific condition 340/540 340/635 .. Condition of electrical apparatus 340/653 ... Electronic circuit or component (1 OR, 2 XR) 370/225 370 : MULTIPLEX COMMUNICATIONS Class FAULT RECOVERY 370/216 370/225 .Bypass an inoperative channel 713/340 (1 OR, 2 XR) 713 : ELECTRICAL COMPUTERS AND DIGITAL PROCESSING Class SYSTEMS: SUPPORT 713/300 COMPUTER POWER CONTROL .Having power source monitoring 713/340 (2 OR, 1 XR) 3 714/4 714 : ERROR DETECTION/CORRECTION AND FAULT Class DETECTION/RECOVERY DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING 714/100 .Reliability and availability 714/1 .. Fault recovery 714/2 ...By masking or reconfiguration 714/3

3 714/40 (1 OR, 2 XR)

714/4

Class 714: ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY

....Of network

	714/100		10055088_CLSTITLES DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
	714/1 714/25		<pre>.Reliability and availabilityFault locating (i.e., diagnosis or testing)</pre>
	714/40		Component dependent technique
3	714/737 Class		OR, 2 XR) : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699 714/724 714/737		PULSE OR DATA ERROR HANDLING .Digital logic testing .Device response compared to fault dictionary/truth table
2		250	OR, 1 XR) : RADIANT ENERGY PHOTOCELLS; CIRCUITS AND APPARATUS .Optical or pre-photocell systemControlled by article, person, or animal
2	307/44 Class 307/43 307/44	307	: ELECTRICAL TRANSMISSION OR INTERCONNECTION SYSTEMS
2	307/64 Class 307/43 307/64	(1 307	OR, 1 XR) : ELECTRICAL TRANSMISSION OR INTERCONNECTION SYSTEMS PLURAL SUPPLY CIRCUITS OR SOURCES .Substitute or emergency source
2	307/80 Class 307/43 307/80	307	OR, 2 XR) : ELECTRICAL TRANSMISSION OR INTERCONNECTION SYSTEMS PLURAL SUPPLY CIRCUITS OR SOURCES .Selective or optional sources
2	324/117R Class	(0 324	OR, 2 XR) : ELECTRICITY: MEASURING AND TESTING MEASURING, TESTING, OR SENSING ELECTRICITY, PE
	324/117	₹	SE .Magnetic saturation (e.g., in field or in amplifier)

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10055088 CLSTITLES

	2		24	10055088_CLSTITLES OR, 1 XR) : ELECTRICITY: MEASURING AND TESTING MEASURING, TESTING, OR SENSING ELECTRICITY, PE
R		324/126		SE .With coupling means (e.g., attenuator, shunt)
		324/127		Transformer (e.g., split core admits conductor carrying unknown current)
	2		24	OR, 1 XR) : ELECTRICITY: MEASURING AND TESTING MISCELLANEOUS
	2		24	: ELECTRICITY: MEASURING AND TESTING FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
	2	324/500	24	OR, 1 XR) : ELECTRICITY: MEASURING AND TESTING FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS .For fault locationBy voltage or current measuring
	2		24	: ELECTRICITY: MEASURING AND TESTING FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS Of individual circuit component or element
	2	324/628 Class 32 324/600		OR, 1 XR) : ELECTRICITY: MEASURING AND TESTING IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RE
SI	PONS	SE		
		324/612		RELATIONSHIPS .Parameter related to the reproduction or fidelity of a signal affected by a circui
t	unc	der test 324/627 324/628		<pre>Shielding effectiveness (SE)Circuit interference (e.g., crosstalk) measurement</pre>
	2	324/751	(1	OR, 1 XR)

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	Class 324/500 324/537 324/750		: ELECTRICITY: MEASURING AND TESTING FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS .Of individual circuit component or elementSystem sensing fields adjacent device under test (DUT)Using electron beam probe
2	324/767 Class 324/500 324/537 324/765 324/766	(2 324	OR, 0 XR) : ELECTRICITY: MEASURING AND TESTING FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS .Of individual circuit component or elementTest of semiconductor deviceWith barrier layer
2	324/767 340/516 Class 340/500 340/501 340/514 340/516	(0 340	<pre>OR, 2 XR) : COMMUNICATIONS: ELECTRICAL CONDITION RESPONSIVE INDICATING SYSTEM .With particular system function (e.g.,</pre>
2	345/55 Class		OR, 2 XR) : COMPUTER GRAPHICS PROCESSING, OPERATOR INTERFACE PROCESSING, AND SELECTIVE VISUAL
DIS	9LAY 345/30 345/55		SYSTEMS PLURAL PHYSICAL DISPLAY ELEMENT CONTROL SYSTEM (E.G., NON-CRT) .Display elements arranged in matrix (e.g., rows and columns)
2	345/84 Class		OR, 0 XR) : COMPUTER GRAPHICS PROCESSING, OPERATOR INTERFACE PROCESSING, AND SELECTIVE VISUAL
DIS	PLAY		SYSTEMS
	345/30		PLURAL PHYSICAL DISPLAY ELEMENT CONTROL SYSTEM
	345/55		<pre>(E.G., NON-CRT) .Display elements arranged in matrix (e.g., rows and columns)</pre>
	345/84		Light-controlling display elements

10055088_CLSTITLES OPTICAL FREQUENCY CONVERTER

	359/326		OPTICAL FREQUENCY CONVERTER
2	361/104 Class	(1 361	OR, 1 XR) : ELECTRICITY: ELECTRICAL SYSTEMS AND DEVICES
	361/1 361/103 361/104		SAFETY AND PROTECTION OF SYSTEMS AND DEVICES .Circuit interruption by thermal sensingWith fuse
2	361/154 Class		OR, 2 XR) : ELECTRICITY: ELECTRICAL SYSTEMS AND DEVICES
	361/139 361/143		CONTROL CIRCUITS FOR ELECTROMAGNETIC DEVICES .Systems for magnetizing, demagnetizing, or controlling the magnetic field
	361/152 361/154		Including means to establish plural distinct
			current levels (e.g., high, low)
2	365/189	365 .01	OR, 1 XR) : STATIC INFORMATION STORAGE AND RETRIEVAL READ/WRITE CIRCUIT .Testing
2		370	OR, 0 XR) : MULTIPLEX COMMUNICATIONS FAULT RECOVERY .Bypass an inoperative station
2	370/216 370/225	370	OR, 1 XR) : MULTIPLEX COMMUNICATIONS FAULT RECOVERY .Bypass an inoperative channelSpare channel
2	702/35 Class 702/1 702/33 702/35	702	OR, 0 XR) : DATA PROCESSING: MEASURING, CALIBRATING, OR TESTING MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT .Mechanical measurement systemFlaw or defect detection
2	703/2 Class 703/2		OR, 2 XR) : DATA PROCESSING: STRUCTURAL DESIGN, MODELING, SIMULATION, AND EMULATION MODELING BY MATHEMATICAL EXPRESSION

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2	714/11 Class 714/100	714	10055088_CLSTITLES OR, 1 XR) : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
	714/1 714/2 714/3 714/10 714/11		 .Reliability and availability Fault recovery By masking or reconfiguration Of processor Concurrent, redundantly operating processors
2	714/2 Class 714/100	714	OR, 2 XR) : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
	714/1 714/2		<pre>.Reliability and availabilityFault recovery</pre>
2	714/26 Class 714/100	714	OR, 0 XR) : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
	714/1 714/25		<pre>.Reliability and availabilityFault locating (i.e., diagnosis or testing)</pre>
	714/26		Artificial intelligence (e.g., diagnostic expert system)
2		714	: ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699 714/724		PULSE OR DATA ERROR HANDLING .Digital logic testing
2	714/734 Class 714/699 714/724 714/734	714	OR, 2 XR) : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY PULSE OR DATA ERROR HANDLING .Digital logic testingStructural (in-circuit test)
2	714/738 Class		OR, 2 XR) : ERROR DETECTION/CORRECTION AND FAULT

DETECTION/RECOVERY

PULSE OR DATA ERROR HANDLING

714/699

10055088_CLSTITLES .Digital logic testing ..Including test pattern generator

714/724 714/738